Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
09/911,375	FURUKAWA, HIDEYUKI
Examiner	Art Unit
Esaw T. Abraham	2133

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	SEARCHED			
Class	Subclass	Date	Examiner	
. 714	763, 25, 48	5/19/2005	EA	
	:			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
714	763	5/19/2005	EA		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
East, NPL (IEEE search), inventor's search was conducted for double patenting. No double patenting issue was found.	5/19/2005	EA			
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